Search Notes



Application/Control No.	Applicant(s)/Patent under Reexamination	
10/667,372	TAKAHASHI, TOSHIHIDE	
Examiner	Art Unit	

2875

Anabel M. Ton

SEARCHED				
Class	Subclass	Date	Examiner	
362	updated	1/3/2006	АТ	
	-			

INTERFERENCE SEARCHED				
Subclass	Date	Examiner		
see	1/3/2006	ΑТ		
attached				
	Subclass see	Subclass Date see 1/3/2006		

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
	·			
	:			